

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**Applicants:** A. Bhavnagarwala et al.

**Examiner:** West, Jeffrey R.

**Serial No.:** 10/643,193

**Group:** Art Unit 2857

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**Docket:** YOR920030289US1 (8728-635)

**For:** **CIRCUITS AND METHODS FOR CHARACTERIZING RANDOM  
VARIATIONS IN DEVICE CHARACTERISTICS IN SEMICONDUCTOR  
INTEGRATED CIRCUITS**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313

**AMENDMENT UNDER 37 CFR 1.116**

This paper is in response to the Decision on Appeal dated March 23, 2011.